

System Overview

Description /	Мо	del				Serial	Number	
CCD Head	D	U 9	70P	-	BVF	CCD-	22120	
TE Cooler performance	(*)			/lode	erate	High	Ultra-high	-
Accessories	Pov	wer Su	pply Un	it	PS -24		PS -25	•
1	SO-		LM-			MFL-		
Serial/Batch Number			v.					
Other								

Sensor types are defined in Table 1 using the last two letters in box Model Number.

CCD Details

Manufac	turer / Model No.	Pixels	Serial Number
E2V	CCD207-00	1600x200, 16μm x 16μm	12242-04-42
E2V	CCD207-10	1600x400, 16µm x 16µm	
E2V	CCD42-10	2048x512, 13.5μm x 13.5μm	
E2V	CCD30-11	1024x256, 26μm x 26μm	

Special Feature	(*)		(~)
NIMO		Other (specify)	
Fringe Suppression	-	Custom Cables	
Shielded Anti-Blooming			

Window Variant	(~)		(~)
VUV-UV Parallel		NUV-Enhanced Parallel	
Broadband VUV-NIR Wedged		Broadband VUV-NIR Parallel	
Broadband VIS-NIR Wedged		Broadband VIS-NIR Parallel	
VIS-NIR Enhanced Wedged		Bose-Einstein 780nm Wedged	
None		Other	

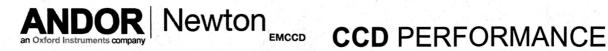
System Sensitivity •1

A/D Rate (MHz All 16 bit)	Preamp setting	(EM) Output eles per A/D count	High Sensitivity (HS) Output eles per A/D count
3	x1	22.7	4.1
3	x2	11.7	2.1
3	x4	5.5	1.0
1.0	x1	19.9	3.4
1.0	x2	10.2	1.6
1.0	x4	5.0	0.8
0.05	x1	19.8	3.4
0.05	x2	10.1	1.6
0.05	x4	5.0	0.8

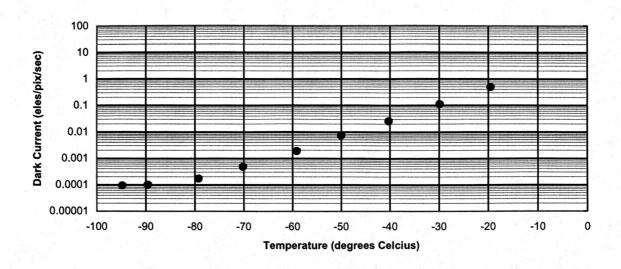
Summary of System Test Data

Readout Noise +2 and Base Mean Level

A/D Rate (MHz All 16 bit)	Output Amplifier	Single Pixel Noise electrons	Full Vert Bin Noise electrons	Base Level (Counts)
3	EM	37.7	37.0	1537
3	HS	9.8	9.5	3116
1.0	EM	20.4	19.6	1862
1.0	HS	6.0	5.9	1279
0.05	EM	8.1	8.0	1699
0.05	HS	2.9	2.9	1274
Saturation	Signal per p	ixel 19	2888 Electro	ns/pixel



CCD Dark Current



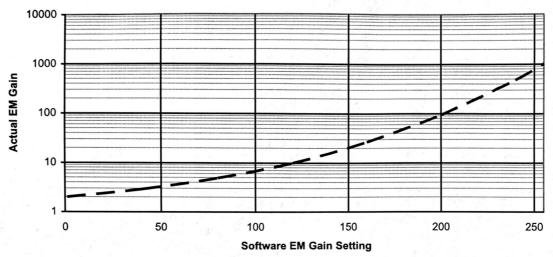
@ Sensor Temperature of •5	0.000094	electrons/pixel/sec			
@ Sensor Temperature of ◆5	-94.82	°C	16.0	°C cooling water	
		With PS-25			
CCD Dark Current Uniformity better than ◆6	0.0013	electrons/pixel/sec			

Linearity and Uniformity

Linearity better than ◆7	1	% over 16 bits
Response Uniformity better than ▶8	0.69	%

EMCCD Gain Characteristics +9

Electron Multiplication Gain Curve at -70°C



Response Defects

White/Black Spots ♦ 10			(X,Y)
Centroid Number of Pixels	1	Centroid	Number of Pixels
(X , X) (, ,)	X)))))))))
X , X) X X X X X X X X X X X X X X X X	♦11 Column	numbers indicated.	
Traps ♦12	Column	numbers indicated.	X



Dark Current Defects

Hot Spots +13			(X,Y)
Centroid	Number of Pixels	Centroid	Number of Pixels
(X		
Hot Columns •1	4 Column nur	nbers indicated X	X

Test Conditions

Readout Noise tested at	-80	°C with	16	°C cooling water
Base Mean Level measured at	-80	°C with	16	°C cooling water
Dark Current Uniformity tested at	-50	°C with	16	°C cooling water
Blemishes tested at	-50	°C with	16	°C cooling water

Additional Comments



System Passed for Shipping

Signed

Date

C.KELZ

1 September 2018

Hardware	System Configuration	FPGA				
Version #	AH	20.24				
Shipping						
Software	Solis	SDK				
Version #						
Testing						
Software	Solis	SDK				
Version #	4.30.30045.0	2.102.33045.0				

∇ Table 1; Key code to define the meanings of the last two letters in the Model Number

Sensor Options			
OE	Open electrode	BV	BI + VIS (550nm) optimised)
FI	Front illuminated (FI)	BR	BI + NIR (850) optimised
UV	FI+UV coating	BR-DD	BI + NIR +deepdepletion
FO	FI + Fibre optic	BN	BI with no AR coating
FI-DD	FI + deep depletion	FK	Fast Kinetics (masked; 3011 only)
BU2	Back Illuminated (BI) + 250nm UV optimised	KT	Kodak FI coating
BU	BI + UV (350nm) optimised		



Performance Notes

- Sensitivity is calculated in photoelectrons per A/D count from measurements of the Photon Transfer Curve.
- Readout Noise is measured for both single pixel (SP) and fully vertically binned (FVB) with the CCD in darkness at temperature indicated and minimum exposure time. Noise values are quoted for the highest available pre-amplifier gain selection [PAG], the noise performance will vary with PAG selection.
- Average electronic DC offset for CCD in darkness at temperature indicated and minimum exposure time under dark conditions measured by single pixel (SP) for imaging systems and by (FVB) for spectroscopic systems.
- Dark current falls exponentially with temperature. However, for a given temperature the actual dark current can vary by more than an order of magnitude from device to device. The devices are specified in terms of minimum dark current achievable rather than minimum temperature.
- ◆5 Minimum temperature achieved for thermoelectric (TE) cooler set to maximum value with water cooling
- RMS (root mean square) deviation of dark current for fully binned operation for spectroscopic cameras, or full resolution image for imaging cameras, under dark conditions at temperature indicated (pixel/column defects not included). This variation is mainly cosmetic since it is fully subtractable without significant loss of performance.
- ◆7 Linearity is measured from a plot of counts vs. signal up to the saturation point of the system. Linearity is expressed as a percentage deviation from a straight line fit.
- ♠8 RMS (root mean square) deviation from the average response of the CCD in fully binned operation for spectroscopic cameras, or full resolution image for imaging cameras, illuminated with uniform white light (defects not included).
- ◆9 The Electron multiplication gain characteristics on the sensor. Note that the gain achieved varies with operating temperature and may reduce slowly over time.
- ♦10 A spot can be up to 3 pixels in size. White/black spots have signals >25% above/below the average (25% contrast) with uniform illumination across the sensor.
- ◆11 Columns whose signals have >10% contrast in binned operation with uniform illumination across the sensor for spectroscopic cameras, ≥ 10 black spots per column for imaging cameras.
- ♦12 Pixels which absorb charge as it is clocked through the defective area. When the light source is switched off, the signal from the trap appears to drop off more slowly than the signal from the surrounding pixels.
- ♦13 A spot can be up to 3 pixels in size. For Grade A devices, hot spots are counted if they exhibit >50 times the maximum specified dark current at the test temperature indicated.
- ♦ 14 A column is considered defective if >10 pixels are affected, or if the column exhibits
 >2 times the maximum specified dark current at the test temperature indicated.